

Search Notes

Application/Control No.

10/626,693

Examiner

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Applicant(s)/Patent under
Reexamination

MEYER, JOHN F.

Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner
update		4/5/2007	AV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	4/5/2007	AV